

UNISONIC TECHNOLOGIES CO., LTD

7NM80 Preliminary Power MOSFET

7.0A, 800V N-CHANNEL SUPER-JUNCTION MOSFET

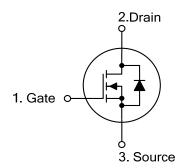
■ DESCRIPTION

The **UTC 7NM80** is a Super Junction MOSFET Structure and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and a high rugged avalanche characteristics. This power MOSFET is usually used at DC-DC, AC-DC converters for power applications.

■ FEATURES

- * $R_{DS(ON)}$ < 0.94 Ω @ V_{GS} = 10V, I_D = 3.5A
- * Fast switching capability
- * Avalanche energy tested
- * Improved dv/dt capability, high ruggedness

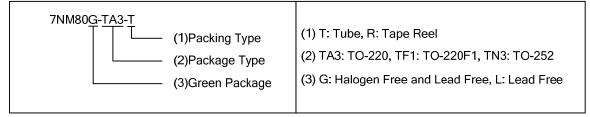




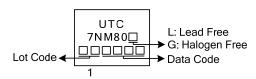
ORDERING INFORMATION

Ordering Number		Dackage	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
7NM80L-TA3-T	7NM80G-TA3-T	TO-220	G	D	S	Tube	
7NM80L-TF1-T	7NM80G-TF1-T	TO-220F1	G	D	S	Tube	
7NM80L-TN3-T	7NM80G-TN3-T	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



■ MARKING



TO-220 TO-220F1 TO-220F1

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■ ABSOLUTE MAXIMUM RATINGS (T_C =25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V_{DSS}	800	V	
Gate-Source Voltage		V_{GSS}	±30	V	
Drain Current	Continuous	I_{D}	7.0	Α	
	Pulsed (Note 2)	I _{DM}	28	Α	
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	420	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	6.2	V/ns	
Power Dissipation	TO-220	P_D	142	W	
	TO-220F1		51	W	
	TO-252		62	W	
Junction Temperature		TJ	+150	°C	
Storage Temperature Range		T _{STG}	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L=159mH, I_{AS} =2.3A, V_{DD} =50V, R_{G} =25 Ω , Starting T_{J} = 25 $^{\circ}$ C.
- 4. $I_{SD} \le 7.0 A$, $di/dt \le 200 A/\mu s$, $V_{DD} \le V_{(BR)DSS}$, $T_J = 25 ^{\circ} C$.

■ THERMAL DATA

PARAMETER		SYMBOL	RATING	UNIT
Junction to Ambient	TO-220	0	62.5	°C/W
	TO-252	θ_{JA}	110	°C/W
Junction to Case	TO-220	θ _{JC}	0.88	°C/W
	TO-220F1		2.45	°C/W
	TO-252		2.01	°C/W

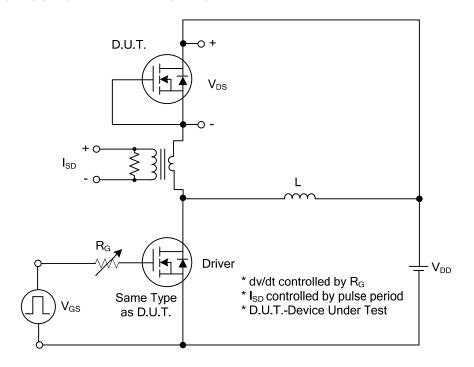
■ **ELECTRICAL CHARACTERISTICS** (T_J=25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage	BV _{DSS}	V_{GS} =0V, I_D =250 μ A	800			V		
Drain-Source Leakage Current	I _{DSS}	V _{DS} =800V, V _{GS} =0V			10	μΑ		
Gate-Source Leakage Current	I _{GSS}	V_{DS} =0V , V_{GS} =±30V			±100	nA		
ON CHARACTERISTICS								
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.5	V		
Drain-Source On-State Resistance	R _{DS(ON)}	$V_{GS} = 10V, I_D = 3.5A$			0.94	Ω		
DYNAMIC PARAMETERS								
Input Capacitance	C _{ISS}			620		pF		
Output Capacitance	Coss	V_{GS} =0V, V_{DS} =25V, f=1.0MHz		244		pF		
Reverse Transfer Capacitance	C_{RSS}			18		pF		
SWITCHING PARAMETERS								
Total Gate Charge (Note 1)	Q_G	-V _{DS} =50V, V _{GS} =10V, I _D =1.3A , -I _G =100μA (Note 1, 2)		46		nC		
Gate to Source Charge	Q_{GS}			5		nC		
Gate to Drain Charge	Q_GD			16		nC		
Turn-ON Delay Time (Note 1)	$t_{D(ON)}$			56		ns		
Rise Time	t_R	V_{DD} =30V, V_{GS} =10V, I_{D} =0.5A,		120		ns		
Turn-OFF Delay Time	$t_{D(OFF)}$	R _G =25Ω (Note 1, 2)		272		ns		
Fall-Time	t_{F}			68		ns		
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS								
Maximum Body-Diode Continuous Current	I_S				7.0	Α		
Maximum Body-Diode Pulsed Current	I _{SM}				28	Α		
Drain-Source Diode Forward Voltage (Note 1)	V_{SD}	I _S =3.5A, V _{GS} =0V			1.4	V		
Body Diode Reverse Recovery Time (Note 1)	t _{rr}	I _S =7.0A, V _{GS} =0V,		450		ns		
Body Diode Reverse Recovery Charge	Q_{rr}	dI _F /dt=100A/µs		6		μC		

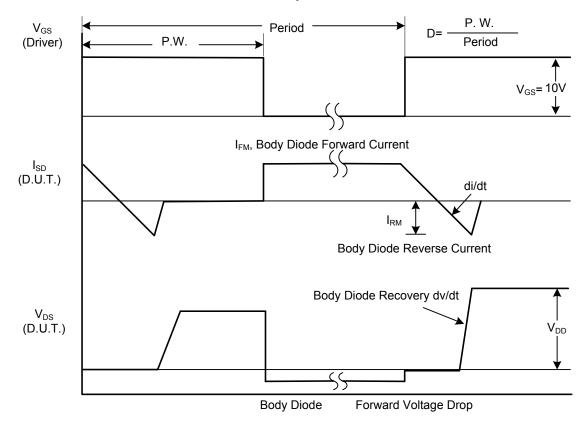
Notes: 1. Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2%.

^{2.} Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

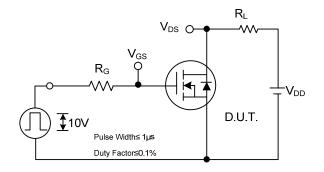


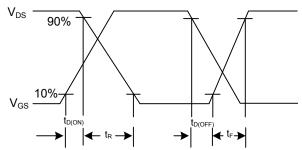
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

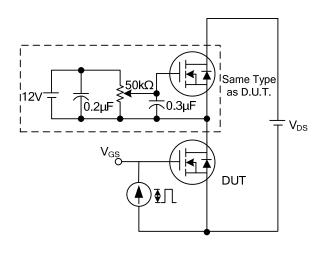
■ TEST CIRCUITS AND WAVEFORMS (Cont.)

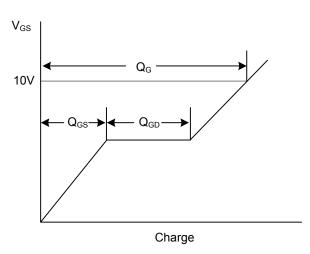




Switching Test Circuit

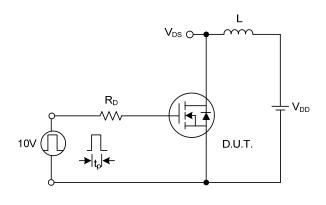
Switching Waveforms

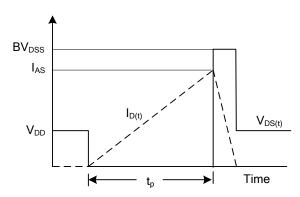




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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